

Toward a high granularity, high counting rate differential read-out RPC

- > Differential strip architecture based on Pestov glass short review
- High granularity differential strip architecture
 - ⁶⁰Co source tests
 - First results from in-beam tests (GSI-Aug. 2009)

Conclusions & Outlook

Differential Strip – Readout Pestov Glass RPC Prototype





RPC

FEE NINO chips



LVDS NIM converter \Rightarrow

⁶⁰Co source test – time resolution differential architecture

Applied High Voltage = 6400 V



⁶⁰Co source test – time resolution differential architecture

Applied High Voltage = 6400 V



In-Beam Tests @ ELBE





Experimental set-up:

- electron beam, 28 MeV, scattered @ 45° by a 18 µm Al foil
- plastic scintillators S5(XP2972), S12(XP2020), S34(XP2020),
- $(2 \times 2 \text{ cm}^2)$ used for active collimation
- signal amplification: differential readout based on NINO chip developed within ALICE Collaboration
- digital converters: CAEN TDC V1290N
- DAQ MBS
- information recorded for 2 central strips



M. Petris et al. CBM Collaboration Meeting, 13-18 October, 2008, Dubna, Russia

High granularity HCRRPC – cross section



Symmetrical structure, differential readout

Active area 46 x 180 mm²

Electrodes: Float glass: 0.5 mm

 2×5 gas gaps; 140 μ m thickness each gap

Readout electrodes: 1 double sided anode and 2 single sided cathodes

made from pcb with copper strips: 72 strips each side:

2.54 mm strip pitch = 1.1 mm strip width + 1.44 mm gap width

High granularity HCRRPC



High granularity HCRRPC



Construction Details





⁶⁰Co source test set-up







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⁶⁰Co signals recorded from one strip without any amplification



⁶⁰Co source test – time resolution RPC transverse strips



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⁶⁰Co source test – time resolution RPC transverse strips



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⁶⁰Co source – Plastic Scintillator Time Resolution



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In-Beam Tests (a) SIS – GSI



- signal amplification: differential readout based on NINO chip developed within ALICE Collaboration
- digital converters: CAEN TDC V1290A
- DAQ MBS
- information recorded for 15 strips readout at both ends,

Events Distribution on Strips







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Time resolution



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Time resolution as a function of strip no.



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Efficiency



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Conclusions and Outlook

• Differential strip readout Pestov Glass RPC prototype

- The in-beam test showed the good performance of the counter with a differential readout based on NINO chip in terms of time resolution ~85 ps (! Including LVDS NIM converter)
 No deterioration of time resolution as a function of counting rate was observed up to ~ 16,000 part/cm²· sec in condition of an uniform illumination of the whole active area of the counter
- We <u>designed</u>, <u>built</u> and <u>tested</u> with ⁶⁰Co source a new configuration of a <u>high granularity, strip read-out, differential high counting rate RPC</u> using thinner glass electrodes, for small polar angles
- 60 Co source and in -beam test showed:
 - excellent time resolution
 - high granularity (multihit performance to be checked in real conditions)
 - preliminary 85% efficiency, not yet at the plateau value (the influence of NINO gain, threshold and electric field distribution to be studied!)
 - counting rate performance under investigation
 - *identical architecture using low resistivity glass electrodes MUST*!
 - differential NINO FEE is completely adequate for this type of architecture.
- In beam tests using:
 - ⁻ Minimum ionizing particles
 - Uniform illumination of the whole counter at high counting rate

In the near future, are mandatory

- Sufficient statistics for a multidimensional studies of the prototype
- Aging tests

Participants

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